


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590642	<b>Applicant(s)/Patent Under Reexamination</b>  TAKAYAMA ET AL.
	<b>Examiner</b>  BRYAN P GORDON	<b>Art Unit</b>  2834

SEARCHED			
Class	Subclass	Date	Examiner
310	313R	3/11/2008	BG

SEARCH NOTES		
Search Notes	Date	Examiner
Searched for "first adj metal adj layer with mesh and second adj metal adj layer"	09/11/2008	BG
Text searched for "mesh\$2 or strip\$2 with pattern with perpendicular with scatter"	01/22/2009	BG

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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